

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 294136US0X PCT		SERIAL NO. 10/589,247		
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				FILING DATE August 14, 2006		GROUP 1616		
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	AW	Office Action issued August 23, 2011, in Japanese Patent Application no. 2006-511711 with English translation.						
	AX							
	AY							
	AZ					<input type="checkbox"/> Additional References sheet(s) attached		
Examiner				Date Considered				
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								